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SERIAL NUMBER 10/757,415	FILING OR 371(c) DATE 01/15/2004 RULE	CLASS 703	GROUP ART UNIT 2123	ATTORNEY DOCKET NO. 04173.0441
APPLICANTS Hisashi Kaneko, Fujisawa-shi, JAPAN; Motoya Okazaki, Tokyo, JAPAN; Hiroyuki Toshima, Saitama-shi, JAPAN;				
** CONTINUING DATA ***** <i>None April 11/29/06</i>				
** FOREIGN APPLICATIONS ***** JAPAN P2003-344526 10/02/2003 <i>April 11/29/06</i>				
IF REQUIRED, FOREIGN FILING LICENSE GRANTED ** 04/19/2004				
Foreign Priority claimed <input checked="" type="checkbox"/> yes <input type="checkbox"/> no 35 USC 119 (a-d) conditions <input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after met Allowance <i>April 11/29/06</i> Verified and Acknowledged Examiner's Signature _____ Initials _____		STATE OR COUNTRY JAPAN	SHEETS DRAWING 10	TOTAL CLAIMS 22
		INDEPENDENT CLAIMS 4		
ADDRESS 22852				
TITLE Simulation circuit pattern evaluation method, manufacturing method of semiconductor integrated circuit, test substrate, and test substrate group				
FILING FEE RECEIVED 1022	FEES: Authority has been given in Paper No. _____ to charge/credit DEPOSIT ACCOUNT No. _____ for following:		<input type="checkbox"/> All Fees <input type="checkbox"/> 1.16 Fees (Filing) <input type="checkbox"/> 1.17 Fees (Processing Ext. of time) <input type="checkbox"/> 1.18 Fees (Issue) <input type="checkbox"/> Other _____ <input type="checkbox"/> Credit	